Evidence for $2k_F$ Electron-Electron Scattering Processes in C oulom b D rag

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M easurements and calculations of C oulomb drag between two low density, closely spaced, twodimensional electron systems are reported. The experimentally measured drag exceeds that calculated in the random phase approximation by a signi cant, and density dependent, factor. Studies of the dependence of the measured drag on the difference in density between the two layers clearly demonstrate that previously ignored $q = 2k_F$ scattering processes can be very important to the drag at low densities and small layer separations.

73.40.-с, 73.20.-г, 73.63.Н s

Interlayer Coulomb interactions between electrons in spatially separated two-dimensional electron systems (2DES) can lead to the condensation of exotic bilayer collective phases which do not occur in single layer system s [1]. A dram atic example of this occurs when the total number of electrons in the bilayer system equals the number of states in the lowest spin-resolved Landau level created by a perpendicular magnetic eld. If the separation between the layers is smallenough, intra-and interlayer C oulom b interactions can com bine to produce a spontaneous interlayer phase coherent state in which there is complete quantum uncertainty as to which layer any given electron is in. This unusual state has been predicted to possess a number of remarkable properties including counter- ow super uidity and Josephsonlike interlayer tunneling. Recent experiments [2,3] have strongly supported these predictions.

In spite of the key role played by interlayer electronelectron interactions in the stabilization of bilayer condensed phases, there have been very few quantitative m easurements of their strength. One relatively new technique [4,5] for making such measurements consists of recording the \drag" voltage V_D which develops in one electron layer in response to a current ow I con ned solely to the other layer. The resulting drag resistance $R_D = V_D = I$ is directly proportional to the interlayer momentum relaxation rate in the system. At low tem – peratures and with closely spaced layers, direct interlayer C oulom b scattering dom inates this rate [4,6], but in general other processes, such as virtual phonon exchange [7{10} and plasm on-enhanced C oulom b scattering [11{13}, can also contribute.

At tem peratures T sm all com pared to the Ferm item – perature T_F the divergent phase space for forw and (q = 0) and backward $(q = 2k_F)$ C oulom b scattering in a clean 2D ES leads to ln (T) corrections to the usual T² dependence of the inverse therm al quasiparticle lifetime [14]. In drag, how ever, the situation is somewhat di erent. M ost importantly, the Fourier transformed bare interlayer C oulom b interaction is exponentially sensitive to the spacing d between the layers: V (q) e $q^d=q$. This

e ectively suppresses scattering processes with momentum transfers in excess of q 1=d. Thus, if $k_{\rm F}\,d>>1$ backward scattering q = $2k_{\rm F}$ processes are unimportant. In this case the drag is dominated by small angle events and one expects [4,6] $R_{\rm D}$ T^2 . This situation was appropriate in most early C oulom b drag experiments [4,5,12]. In this case the ln (T) dependence is absent because the momentum relaxation rate is determined by the electron-electron scattering cross-section weighted by 1 cos q², where is the scattering angle. This factor vanishes rapidly enough at small q to suppress the low angle phase space divergence.

Backward scattering processes can become in portant in drag at low carrier densities and for closely spaced layers since then $k_{\rm F}$ d may be of order or even less than unity. In this case a $T^2\ln\left(T\right)$ temperature dependence of the drag resistance is expected at low T. Although de nitive identi cation of such logarithm ic corrections is di cult, we nonetheless report here strong evidence for $q=2k_{\rm F}$ C oulom b drag scattering processes in low density bilayer system s. This evidence is obtained not from the temperature dependence of the drag, but rather from its sensitivity to the di erent densities in the two 2D layers.

The drag experim ents reported here were perform ed on bilayer 2D E Ss in G aA s/A IG aA s heterostructures. T hese sam ples contain two 18nm GaAs quantum wells separated by a 10nm A $l_{0.9}$ G $a_{0.1}$ A s barrier layer. This double well structure is sandwiched between thick A log G a0;7A s layers which contain Si -doping layers positioned about 220nm from the GaAs quantum wells. At low temperatures each quantum well contains a 2DES of nom inaldensity 5:2 10^{10} cm² and mobility 1 10^{6} cm²=V s. Standard photolithographic techniques were used to pattern a mesa,40 m wide by 400 m long, on the sample. Di used In ohm ic contacts were placed at the ends of arm swhich extend outward from this bar-shaped centralm esa. A selective depletion scheme allows each of these contacts to be connected to the central region through either 2D layer separately [15]. M etal gate electrodes on both sides of the thinned heterostructure sam ple provide control over

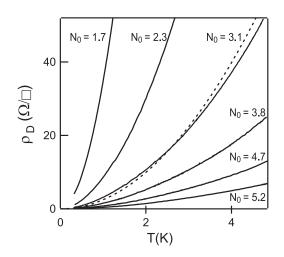


FIG.1. Drag resistivity vs. temperature for six di erent densities N₀. Densities are in units of 10^{10} cm². Dashed line is a least-squares tof the N₀ = 3:1 10^{10} cm² data to _D = AT².

the electron densities N₁ and N₂ of each 2D layer. D rag m easurem ents were perform ed by driving a current, typically 10nA at 13H z, down the bar through one 2D layer while the drag voltage which develops in the other layer is recorded. Considerable care was exercised in order to elim inate spurious contributions to the drag signal arising from the nite tunneling resistance (140 pF) between the layers. No e ect on the drag resistance was found when the role of drive and drag layers were interchanged.

Figure 1 shows the measured drag resistivity $_{\rm D}$ vs: tem perature at six di erent balanced (i.e. $N_1 = N_2$ N₀) densities in the two 2D layers: N₀ = 1:7, 2.3, 3.1, 3.8,4.7, and 5.2 10^{10} cm². A s expected, the drag resistance increases with tem perature and is larger at low er density. The dashed line in the qure represents an unweighted least-squares tofthe $N_0 = 3:1 \quad 10^{10}$ cm ² drag data to a simple quadratic tem perature dependence: $_{D} = AT^{2}$. The tted coe cient A exceeds the simplest theoretical estim ate of C oulom b drag by a factor of 5.9 at this density. This estimate is based upon a model [4,6] which assum es two ideally thin 2D layers separated by the present sam ple's center-to-center spacing of d = 28nm , low tem peratures (T $\,<<\,$ T_F), and a predom inance of sm allangle scattering $(k_F d >> 1)$. The model also treats screening of the interlayer Coulomb interaction in the random phase approximation (RPA) under the assum ption $q_{IF} d >> 1$, with q_{IF} the Thom as Ferm iscreening wavevector. We nd that this model underestim ates the drag at all densities studied and that the shortfall in- 10^{10} cm 2 creases from about a factor of 2 at $N_0 = 8.8$ to a factor of 10 at N $_0 = 1.7 \quad 10^{10}$ cm 2 .

The discrepancy between theory and experiment in the

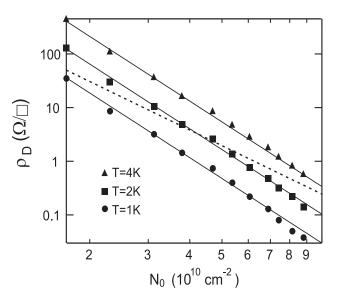


FIG.2. D rag resistivity vs. density at three tem peratures: T = 4K, 2K, and 1K. Solid lines are proportional to N $_0^4$; dashed line proportional to N $_0^3$.

m agnitude of the drag is substantial but not unusual. Sim ilar discrepancies have been reported in electronelectron [4], electron-hole [5], and low density hole-hole [16] sam ples. A lthough phonon exchange can contribute to the drag between 2D electron systems [7{10], it is unlikely to be very in portant here. Experiments in which the phonon contribution was deem ed to be comparable to the C oulom b scattering component show a much sm aller drag resistance than we report here [7,10]. Detailed calculations support this conclusion [9]. Furtherm ore, the phonon contribution has been traditionally identied via the peak it produces in $_{\rm D} = T^2$ vs. T. This peak, which occurs when the mean therm al phonon wavevector is comparable to $2k_{\rm F}$, is not observable in the data presented here.

A nother possible source of the enhanced drag which we observe are higher order m any-body e ects not captured by an RPA treatment of screening. Such e ects generally become m ore important at low density, but there have been few quantitative estimates of their importance in C oulom b drag [17]. To investigate this further we show in Fig. 2 a log-log plot of the drag resistivity $_{\rm D}$ vs. density N₀ at three xed temperatures: T = 1,2, and 4K. The straight solid lines, while merely guides to the eye, represent a N₀⁴ dependence. In contrast, the straight dashed line show sthe N₀³ dependence expected from the simple m odel described above [4,6]. It is apparent that our experimental results are much better approximated by the quartic density dependence.

It is also clear from Fig. 1 that the drag data are not well the the T^2 temperature dependence of the simplest

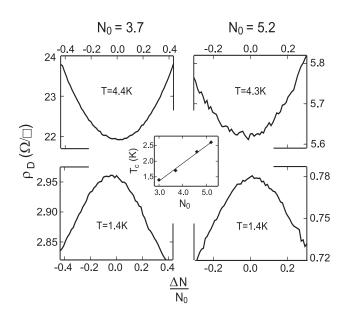


FIG. 3. Sensitivity of drag to antisymmetric density changes N in the two 2D layers. Left panels: A verage density N₀ = 3:7 10^{10} cm⁻². Right panels: N₀ = 5:2 10^{10} cm⁻². For each density, data from two temperatures is shown. Inset: D ensity dependence of the cross-over temperature T_c.

theoretical model. Indeed, we not that an excellent t to the N₀ = 3:1 10^{10} cm² data is provided by _D = AT²ln(T=T₀) with A = 0:411 =2 and T₀ = 1160K. We emphasize, however, that other thing functions also work fairly well (e.g. _D = BT^{1:8}) and that we are not proposing any speci c analytic form.

W e now turn to the dependence of C oulom b drag on antisymmetric changes in the density of the two layers: $N_1 = N_0 + N = 2$ and $N_2 = N_0$ N = 2. Such changes are readily imposed by applying a small dc bias voltage between the two 2D layers [18]. Figure 3 illustrates the e ect of such density in balances on the drag in our sam ples. Data at two di erent average densities N_0 and two tem peratures are show n. As the gure makes clear, very di erent behavior is observed at low and high tem peratures. At high T the drag is found to increase, roughly quadratically, with N. In contrast, low temperatures produce the opposite result: the drag falls, again roughly quadratically, with N.We nd a sm ooth transition between the two regimes and a well-de ned temperature T_c at which the drag is roughly independent of N for small N. The inset to the gure suggests an approximately

linear dependence of the cross-over tem perature T_c on the average layer density N₀. In terms of Ferm i tem peratures, we not that $T_c=T_F$ 0.12 roughly de nes the cross-over tem perature for this sam ple.

W e propose that the results shown in Fig. 3 strongly suggest that $q = 2k_F$ electron-electron scattering processes are in portant to the C oulom b drag in the present

sample. To see this, we begin by noting that in the simple theoretical model presented earlier for comparative purposes, drag increases with N. This is a result of the fact that the drag resistivity in that model is proportional to $(N_1 N_2)^{3=2}$. For small N, the model $_{\rm D} = _{\rm D} = +3$ (N = N₀)²=8. But the validity of leads to this model depends, in part, upon the assumption that $k_F d >> 1$ and the resultant restriction to sm all angle scattering processes. For the present sam ple, how ever, $k_{\rm F}$ d ranges from about 0.9 to 1.6 for the densities used. These values are su ciently small that $2k_F$ scatterings cannot be ignored, especially in view of the large phase space for such events. Furtherm ore, back-scattering processes o er a natural way to understand the imbalance dependence of the drag at low tem peratures. For drag it is the product of the phase space availability in each layer which m atters. If the two 2D system shave the sam e density, their Ferm i surfaces have the sam e diam eter and the phase divergences at $q = 2k_F$ reinforce one another. W hen a density in balance N is in posed, the Ferm isurfaces no longer overlap and the pint phase space product is diminished, dramatically so at low temperature, and this causes the drag to decrease.

At higher tem peratures the phase space singularities are washed out. Owing to the q^2 weighting of the scattering cross-section, the e ect of this therm al sm earing is particularly important for large angle $q = 2k_F$ processes. Indeed, the relative in portance of backward scattering events declines at high tem peratures and the m ean scattering angle dim inishes. For these reasons, it seems plausible that the drag m ight increase with density im balance N in a way sim ilar to that which occurs under the assum ptions of the sm all-angle scattering theory discussed above. In order to make this qualitative argument for a change in sign of the N dependence of drag m ore com pelling, we have perform ed detailed num erical calculations of the drag using the theoretical fram ework originally employed by Gram ila, et al. [4] and Jauho and Sm ith [6]. Although our calculations follow the same Boltzmann equation approach [19] as in these earlier works, we have applied them here to the signi cantly di erent regim e of sam ple param eters (layer separation and density) appropriate to the present experim ents.

Figure 4 shows typical results of our calculations. In the main panel the drag at a density of N₀ = 3:7 10^{10} cm² is shown. These results include the e ect of the nite thickness of the 2D system s [20] and incorporate screening at the RPA level. No attempt wasmade to include phonon or plasmon-related contributions to the drag. As expected, the magnitude of the calculated drag falls short of the experimental results at the same density by a signi cant factor (5). Nonetheless, as the insets demonstrate, the calculations do reproduce the change in sign of the dependence of drag on antisymmetric density changes: N₁ = N₀ + N = 2 and N₂ = N₀ N = 2. In common with the experiment, at low temperatures D

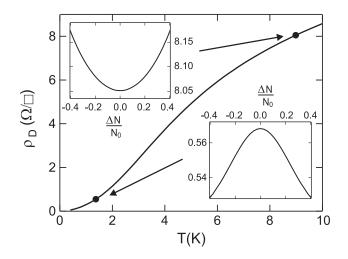


FIG.4. Calculated Coulomb drag vs. temperatures for N $_0$ = 3:7 $10^{10}\,\text{cm}^{-2}$. Insets show dependence of drag on antisymmetric density changes N at low and high temperatures.

falls roughly quadratically with N while at high tem peratures it rises. The calculated cross-over tem perature T_c is about 6.3K; this is about a factor of 4 higher than the experimental value at the same density. It is quite clear from the calculations that the drag at low temperatures contains a strong component from Coulomb backscattering processes sharply peaked around $q = 2k_F$. At high tem peratures this com ponent is reduced and a broad distribution of sm aller scattering angles dom inates the drag. This is clearly demonstrated in Fig. 5 where the drag \intensity" h (q) is plotted vs. m om entum transfer q. (The net drag, D, is obtained by integrating h (q) over all q.) Thus, these calculations strongly support the qualitative argum ent given above and dem onstrate that $q = 2k_F$ backward scattering processes can be very im portant at low temperatures in samples with low electron densities and sm all layer separations. These processes are directly detectable via the unusual dependence of the drag on antisymmetric density changes in the double layer 2D system .

In conclusion, we have measured C oulom b drag in low density 2D electron system s with small layer separations. O ur results show that the drag is substantially larger than theoretical results based on RPA screening of the interlayer C oulom b interaction. We not the level of disagreement to grow steadily worse as the density is reduced. At low temperatures our experimental data and numerical calculations clearly demonstrate that previously ignored large angle $q = 2k_F$ scattering processes can be quite important in C oulom b drag.

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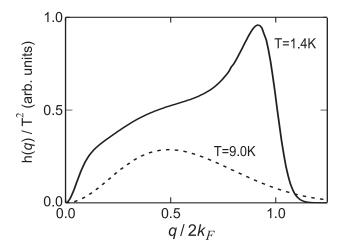


FIG.5. D rag intensity h (q), divided by T², vs. m om entum transfer q at T = 1:4K and 9.0K, for N₀ = 3:7 10^{10} cm². N ote the strong peak near q = $2k_F$ at low tem perature. D rag resistivity _D is the area under these curves.

DE-FG03-99ER45766.

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- [18] An interlayer bias voltage shifts charge between the layers ow ing to the interlayer capacitance. This e ect is easily calibrated by observing the magneto-oscillations of the resistivity in each layer as the bias is applied.
- [19] Unlike Jauho and Sm ith [6], however, we include the full tem perature dependence of the susceptibility functions. This has a signi cant quantitative im pact on the drag at high tem peratures.
- [20] The appropriate form factors [6] were computed based upon calculations of the subband wavefunctions in local density approximation.